



Title of Change:	Qualification of ON Semiconductor facility in Carmona, Philippines as an additional Final Test Location for former AXSEM Product AX5243.													
Proposed first ship date:	30 September 2017 <i>or earlier after customer approval</i>													
Contact information:	Contact your local ON Semiconductor Sales Office or <Tamara.Olney@onsemi.com>													
Samples:	Contact your local ON Semiconductor Sales Office													
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Paul.Syndergaard@onsemi.com>													
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.													
Change Part Identification:	Affected products will be identified with date code.													
Change category:	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____													
Change Sub-Category(s):	<input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Material Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Shipping/Packaging/Marking <input checked="" type="checkbox"/> Other: Tester Equipment Change													
Sites Affected:	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input checked="" type="checkbox"/> ON Semiconductor site(s) : ON Carmona, Philippines _____													
Description and Purpose:														
AXSEM AG was acquired by ON Semiconductor in July, 2015. To expand probe capacity, ON Semiconductor Carmona, Philippines will be added as a final test location for the below mentioned devices.														
<table border="1"> <thead> <tr> <th>Changes</th> <th>Before Change Description</th> <th>After Change Description</th> </tr> </thead> <tbody> <tr> <td>Tester Platform</td> <td>Ocelot Inovys</td> <td>uFlex Analog/Full</td> </tr> <tr> <td>Tester Flow</td> <td>Ambient Only</td> <td>Ambient and QC Ambient</td> </tr> <tr> <td>Carrier Tape</td> <td>C-PAK Item No. 11QN0103 - QFN0400X0400 - CL3 - 22X6 - L420 - W12</td> <td>Advantek ML0404-AC410.P1 (CB-75574)</td> </tr> </tbody> </table>			Changes	Before Change Description	After Change Description	Tester Platform	Ocelot Inovys	uFlex Analog/Full	Tester Flow	Ambient Only	Ambient and QC Ambient	Carrier Tape	C-PAK Item No. 11QN0103 - QFN0400X0400 - CL3 - 22X6 - L420 - W12	Advantek ML0404-AC410.P1 (CB-75574)
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Reliability Data Summary:														
Reliability Data can be made available upon request.														
Electrical Characteristic Summary:														
Electrical Correlation Data can be made available upon request.														
List of Affected Standard Parts:														
Part Number		Qualification Vehicle												
AX5243-1-TA05		7435A												
AX5243-1-TW30		7435A												